

Exams

February 3

March 3

April 28

June 30

Exam

Four questions, two from the online list.

Calculator is ok. No notes.

Explain some concept:

(tunnel contact, indirect band gap, thermionic emission, inversion, threshold voltage, ...)

Perform a calculation:

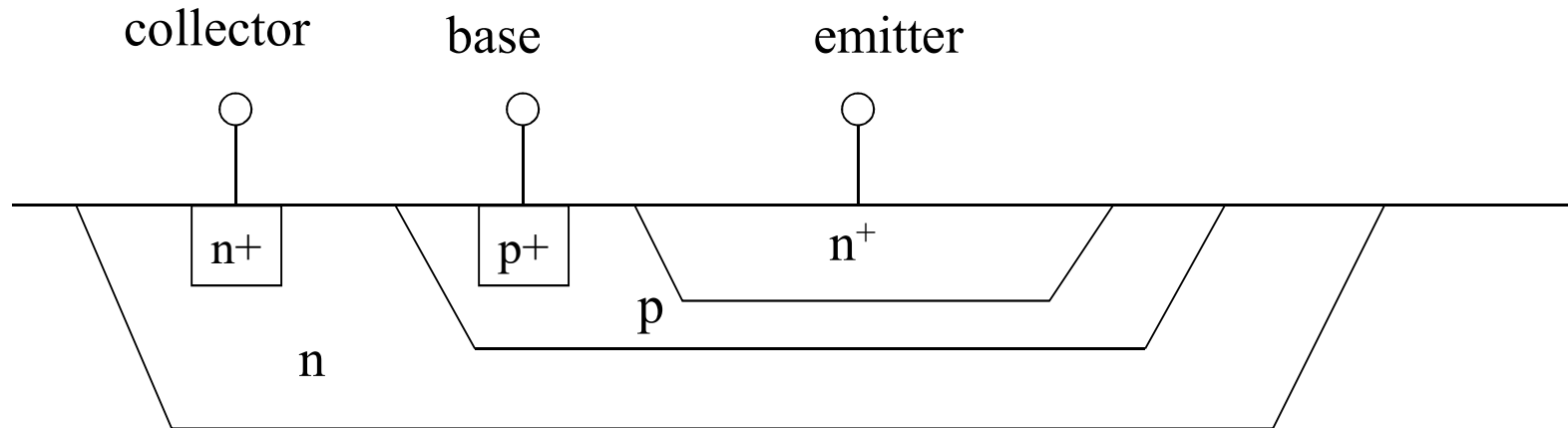
(concentration of minority carriers, integrate charge density to find electric field, ...)

Explain how a device works:

(JFET, MESFET, MOSFET, laser diode, bipolar transistor, LED, Schottky diode, Heterojunction bipolar transistor, ...)

bipolar transistors

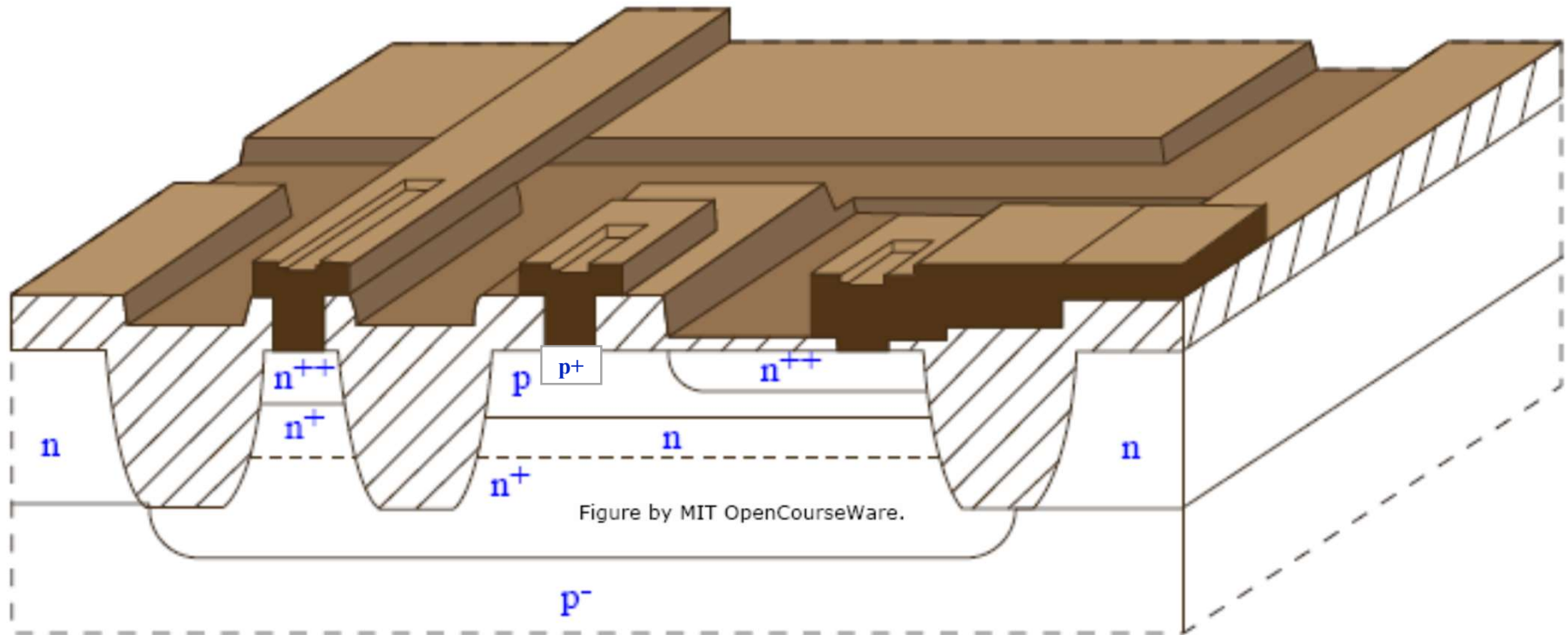
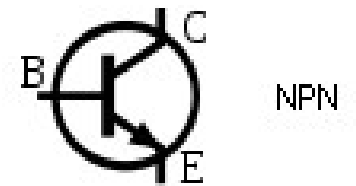
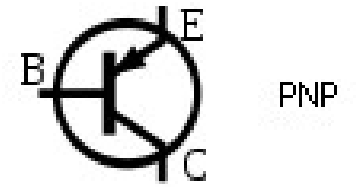
npn transistor



lightly doped p substrate

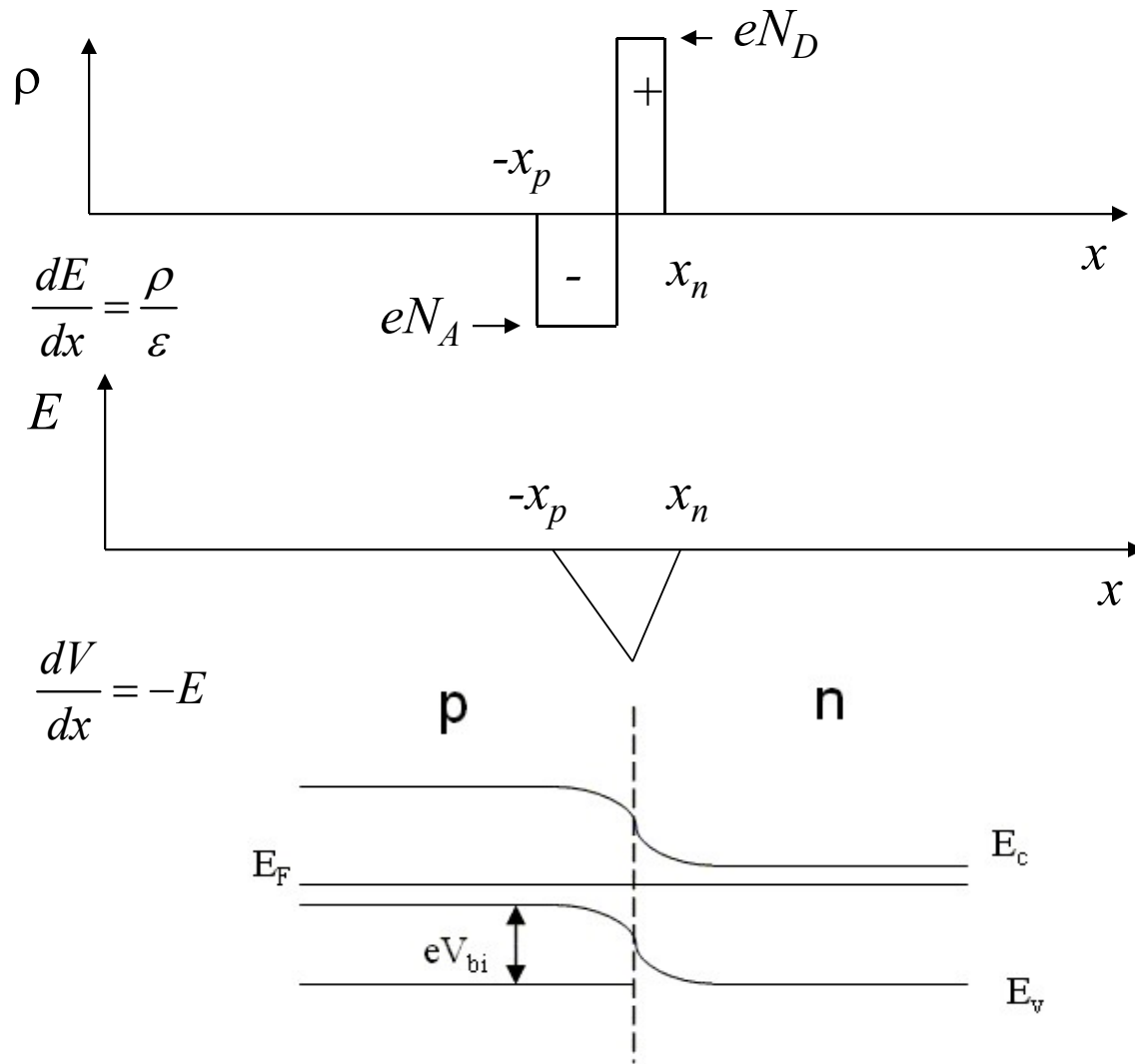
Used in front-end high-frequency receivers (mobile telephones).

bipolar transistors



Oxide isolated integrated BJT - a modern process

abrupt junction



$$eV_{bi} = k_B T \ln \left(\frac{N_D N_A}{n_i^2} \right)$$

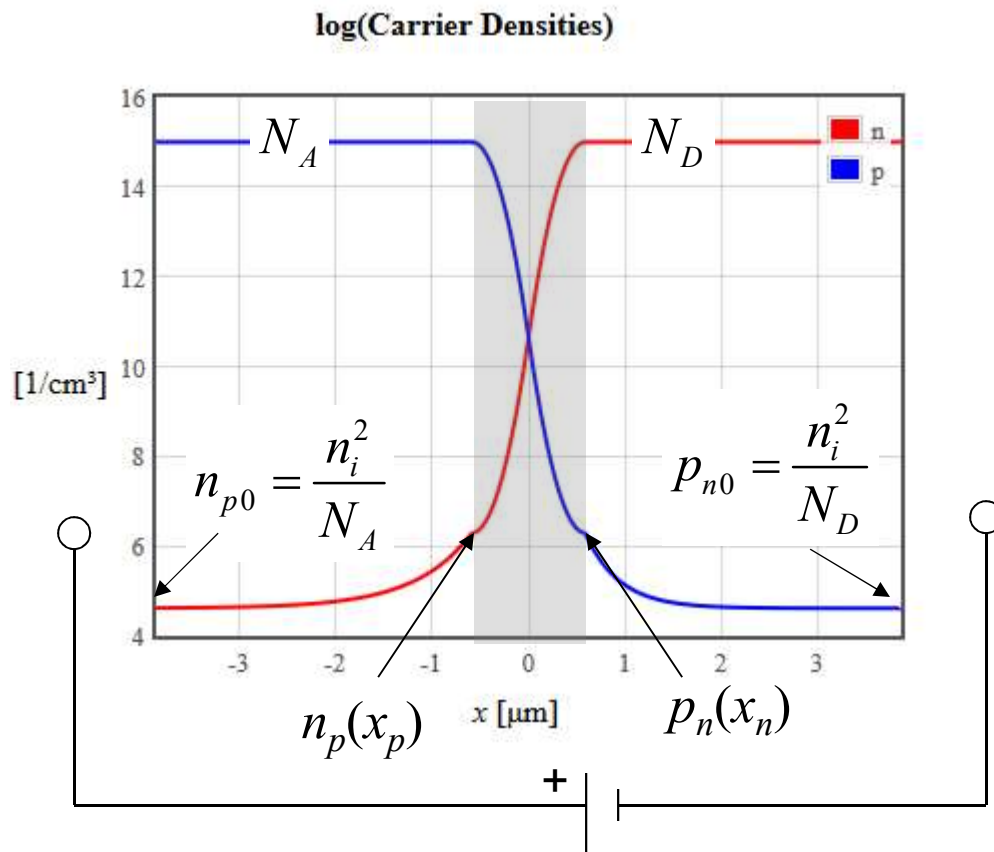
$$E = -\frac{eN_A}{\epsilon} (x + x_p) \quad -x_p > x > 0$$

$$E = \frac{eN_D}{\epsilon} (x - x_n) \quad 0 > x > x_n$$

$$V = \frac{eN_A}{\epsilon} \left(\frac{x^2}{2} + xx_p \right) \quad -x_p > x > 0$$

$$V = \frac{-eN_D}{\epsilon} \left(\frac{x^2}{2} - xx_n \right) \quad 0 > x > x_n$$

Forward bias, $V > 0$



Electrons and holes are driven towards the junction.
The depletion region becomes narrower

$$n_p(x_p) = N_D \exp\left(\frac{-e(V_{bi} - V)}{k_B T}\right)$$

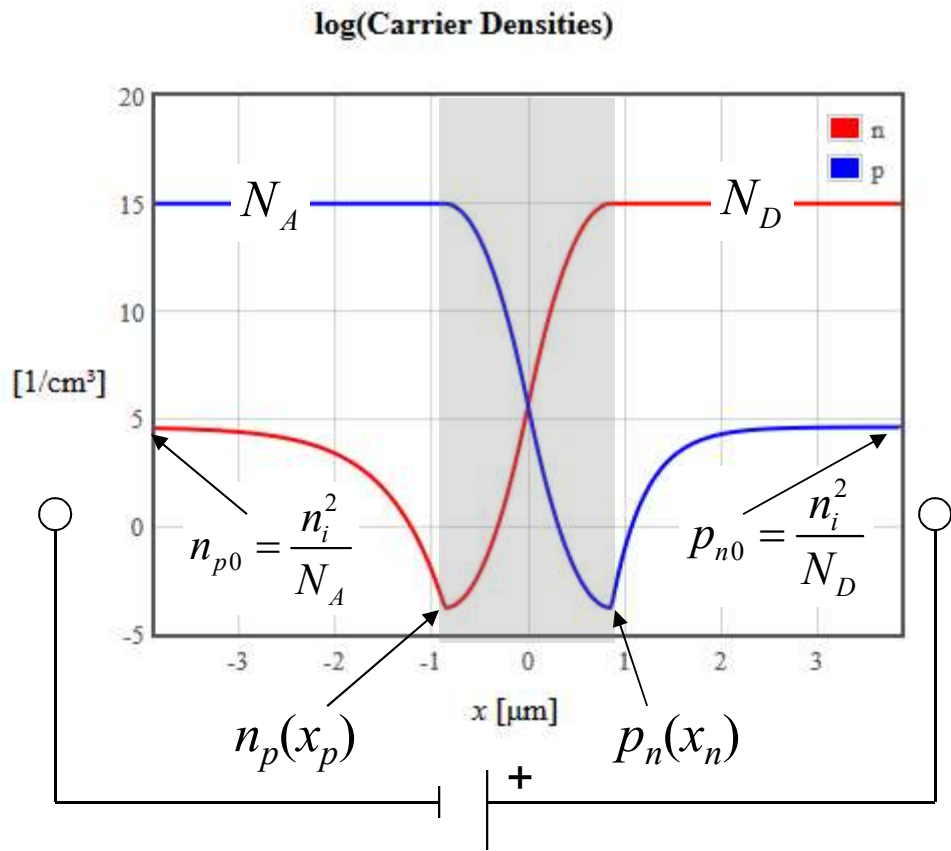
$$= n_{p0} \exp\left(\frac{eV}{k_B T}\right)$$

$$p_n(x_n) = N_A \exp\left(\frac{-e(V_{bi} - V)}{k_B T}\right)$$

$$= p_{n0} \exp\left(\frac{eV}{k_B T}\right)$$

Minority electrons are injected into the p-region
Minority holes are injected into the n-region

Reverse bias, $V < 0$



Electrons and holes are driven away from the junction.
The depletion region becomes wider

$$n_p(x_p) = N_D \exp\left(\frac{-e(V_{bi} - V)}{k_B T}\right)$$

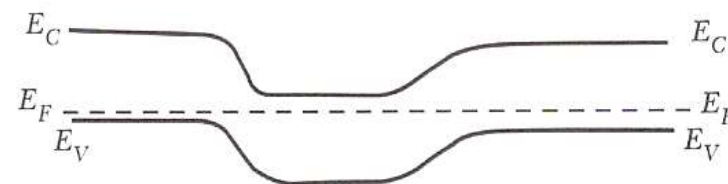
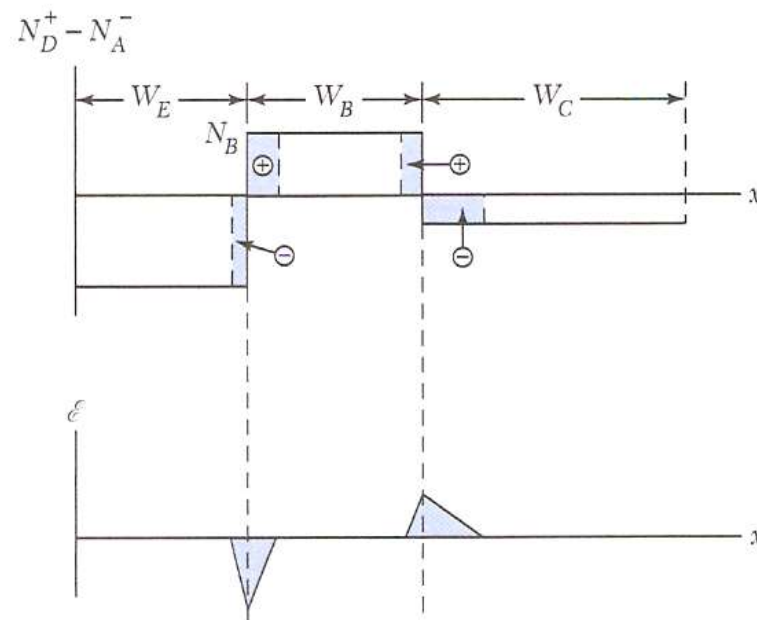
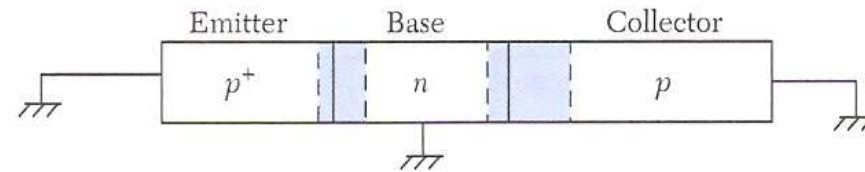
$$= n_{p0} \exp\left(\frac{eV}{k_B T}\right)$$

$$p_n(x_n) = N_A \exp\left(\frac{-e(V_{bi} - V)}{k_B T}\right)$$

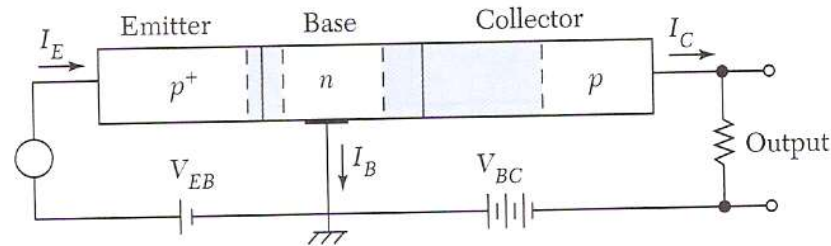
$$= p_{n0} \exp\left(\frac{eV}{k_B T}\right)$$

Minority electrons are extracted from the p-region by the electric field
Minority holes are extracted from the n-region by the electric field

pnp transistor, no bias

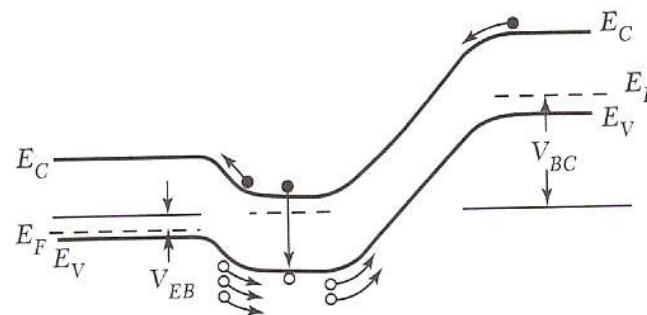
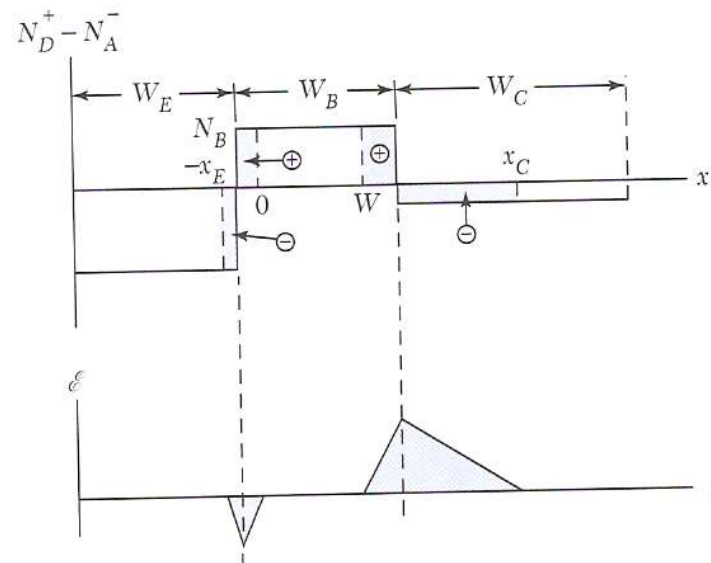


pnp transistor, forward active bias

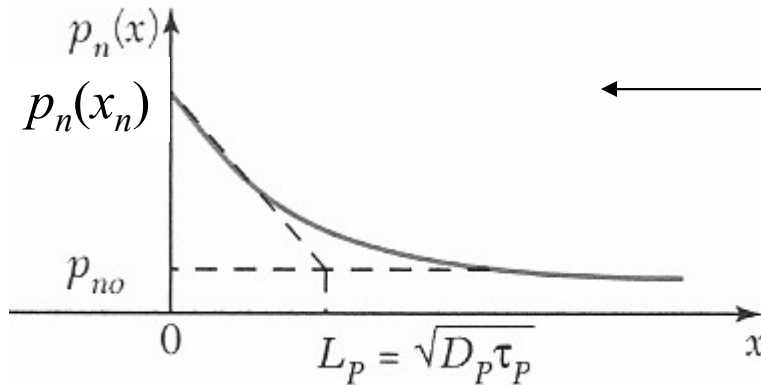


Always dissipate power due to the forward bias

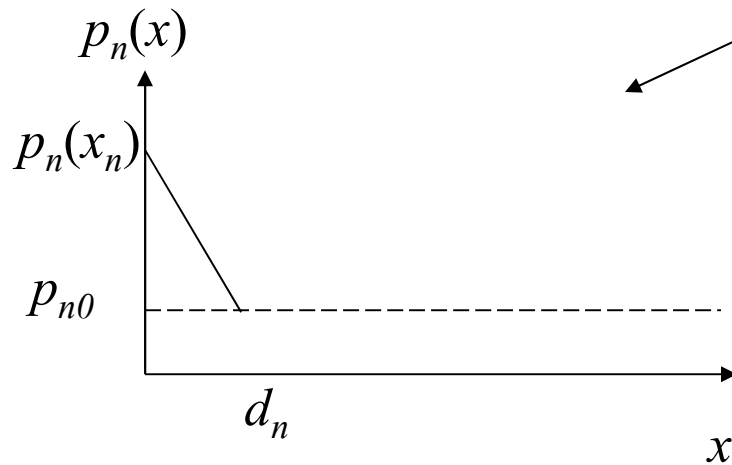
The base-emitter voltage controls the minority carriers injected from the emitter to the base. These diffuse to the base-collector junction and are swept into the collector.



Long/Short diode



← Long diode $d_n \gg L_p$



Short diode

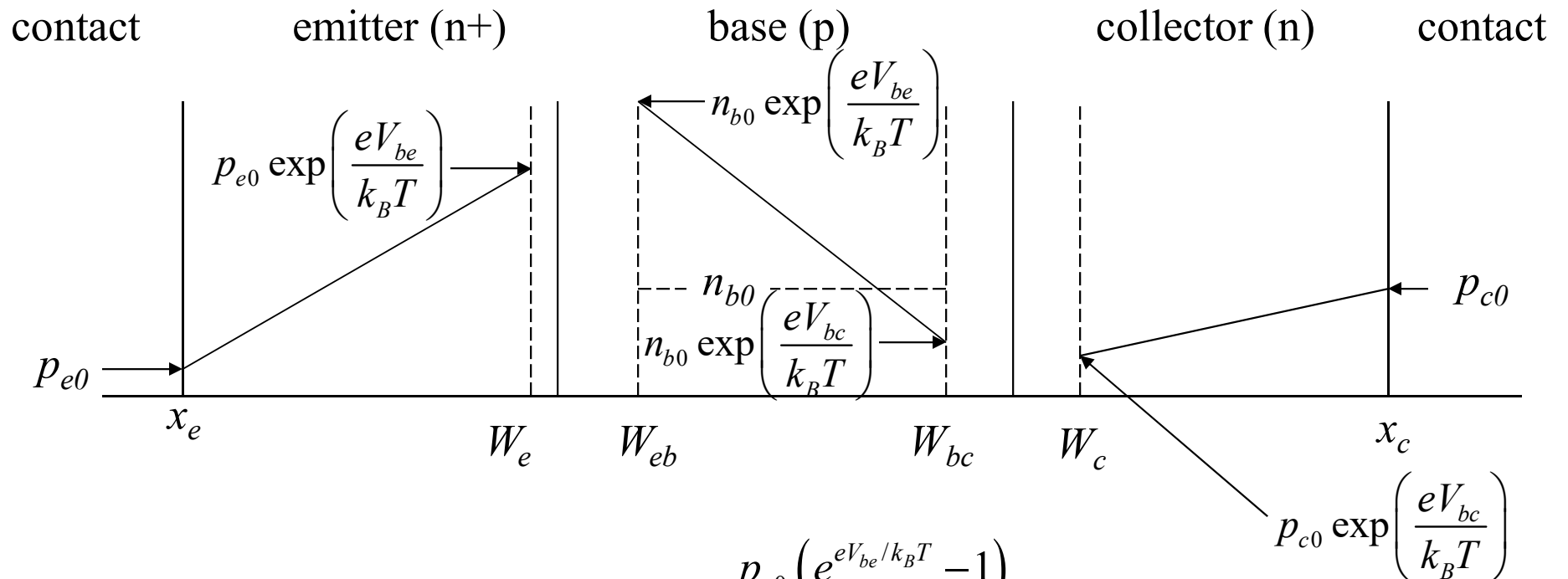
$d_n \ll L_p$

Metal contact is much closer to the depletion region than the diffusion length

$$J_{diff,p} = eD_p \frac{dp}{dx}$$

$$J_{diff,p} = eD_p \frac{dp}{dx} = eD_p \frac{(p_n(x_n) - p_{n0})}{d_n}$$

Minority carrier concentration



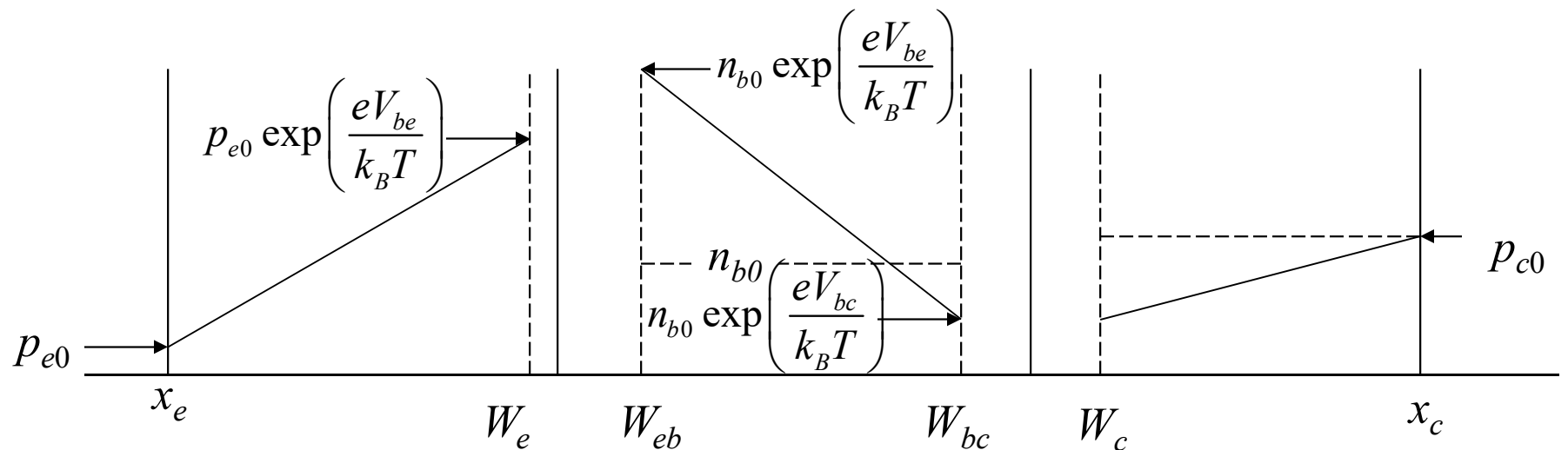
$$I_{Ep} = eA_{be}D_p \frac{p_{e0} \left(e^{eV_{be}/k_B T} - 1 \right)}{W_e - x_e}$$

$$I_{En} = -eA_{be}D_n \frac{n_{b0} \left(e^{eV_{be}/k_B T} - e^{eV_{bc}/k_B T} \right)}{W_{bc} - W_{be}}$$

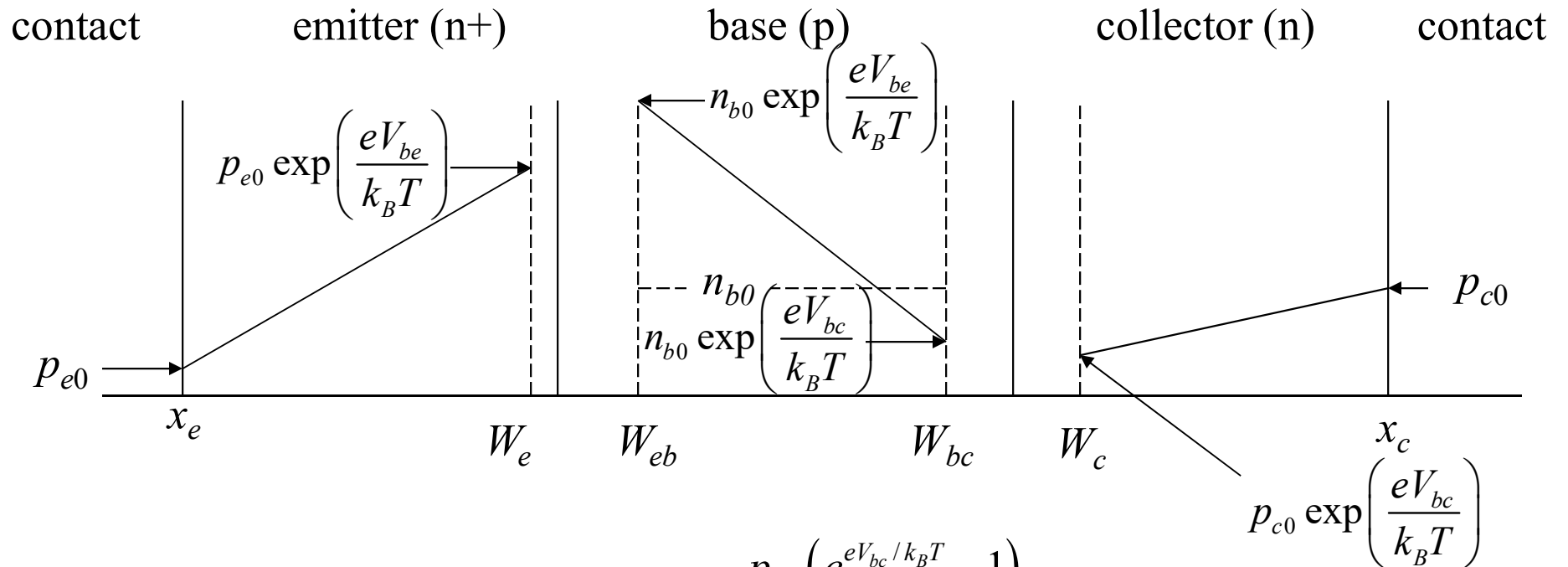
Emitter current

$$I_E = I_{En} + I_{Ep} = \left[\frac{eA_{be}D_p p_{e0}}{W_{eb} - x_e} + \frac{eA_{be}D_n n_{b0}}{W_{bc} - W_{be}} \right] \left(e^{eV_{be}/k_B T} - 1 \right) - \frac{eA_{be}D_n n_{b0}}{W_{bc} - W_{be}} \left(e^{eV_{bc}/k_B T} - 1 \right)$$

$$I_E = I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - \alpha_R I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right)$$



Collector current



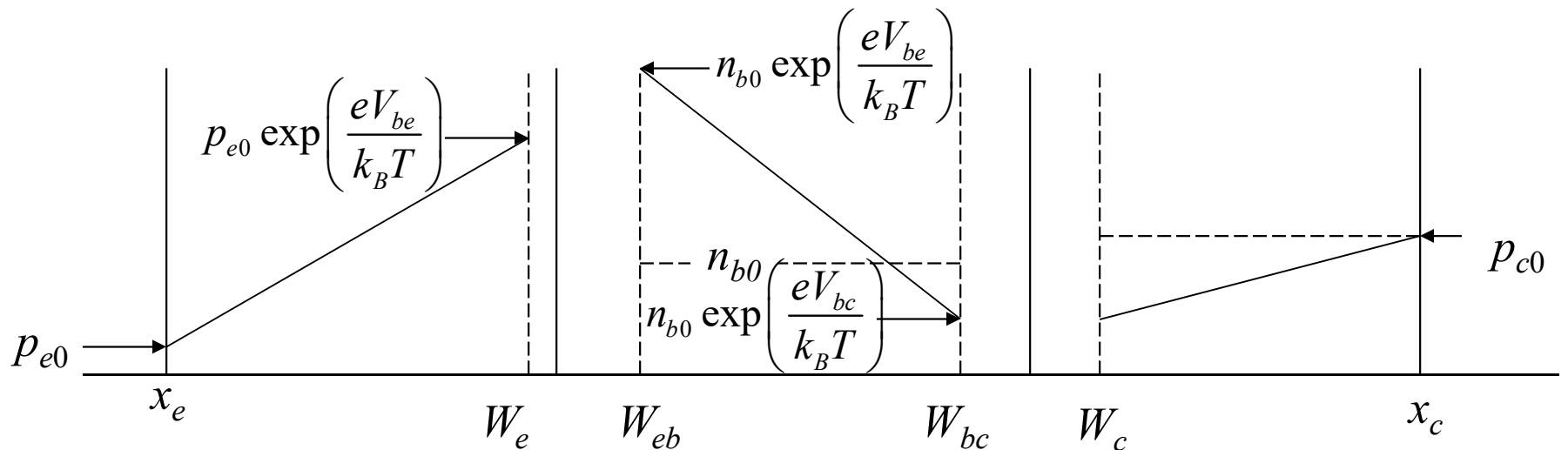
$$I_{cp} = -eA_{bc}D_p \frac{p_{c0} \left(e^{eV_{bc}/k_B T} - 1 \right)}{x_c - W_c}$$

$$I_{cn} = -eA_{bc}D_n \frac{n_{b0} \left(e^{eV_{be}/k_B T} - e^{eV_{bc}/k_B T} \right)}{W_{bc} - W_{eb}}$$

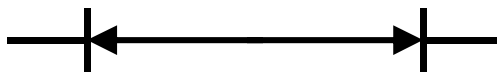
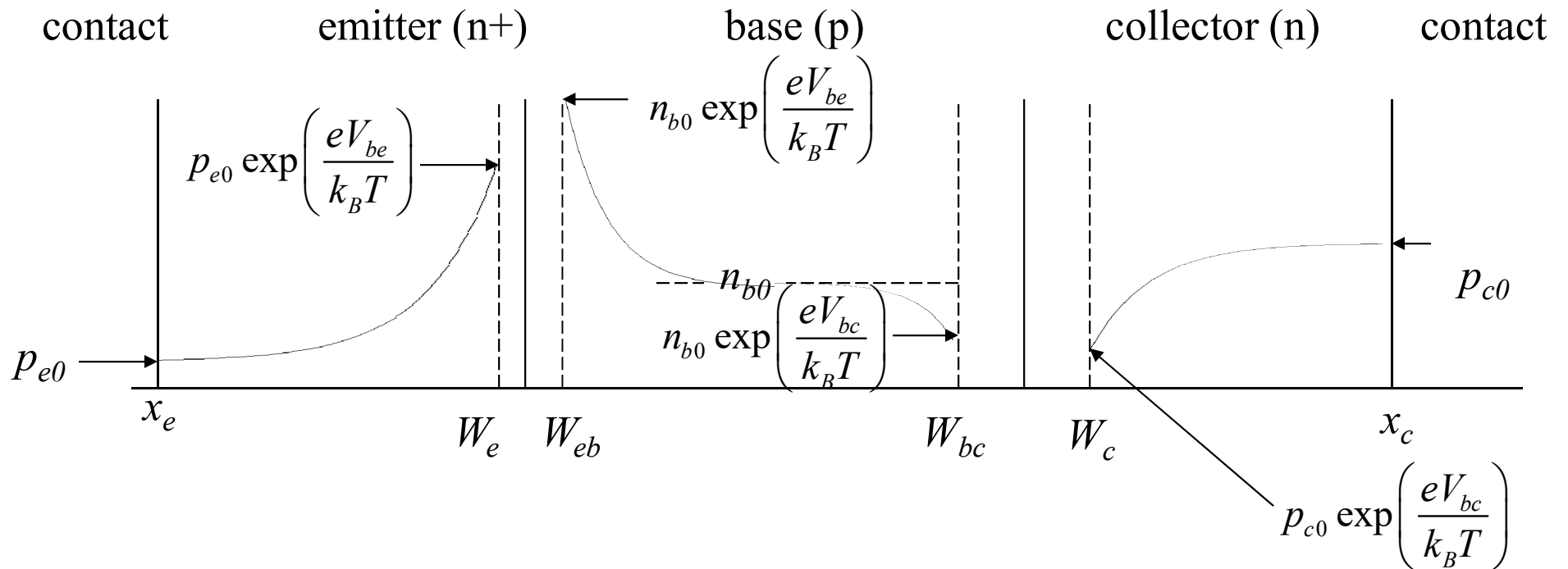
Collector current

$$I_c = I_{cp} + I_{cn} = \frac{eA_{bc}D_n n_{b0}}{W_{bc} - W_{be}} \left(e^{eV_{be}/k_B T} - 1 \right) - \left[\frac{eA_{bc}D_p p_{c0}}{x_c - W_c} + \frac{eA_{bc}D_n n_{b0}}{W_{bc} - W_{be}} \right] \left(e^{eV_{bc}/k_B T} - 1 \right)$$

$$I_c = I_{cp} + I_{cn} = \alpha_F I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right)$$



Not an npn transistor

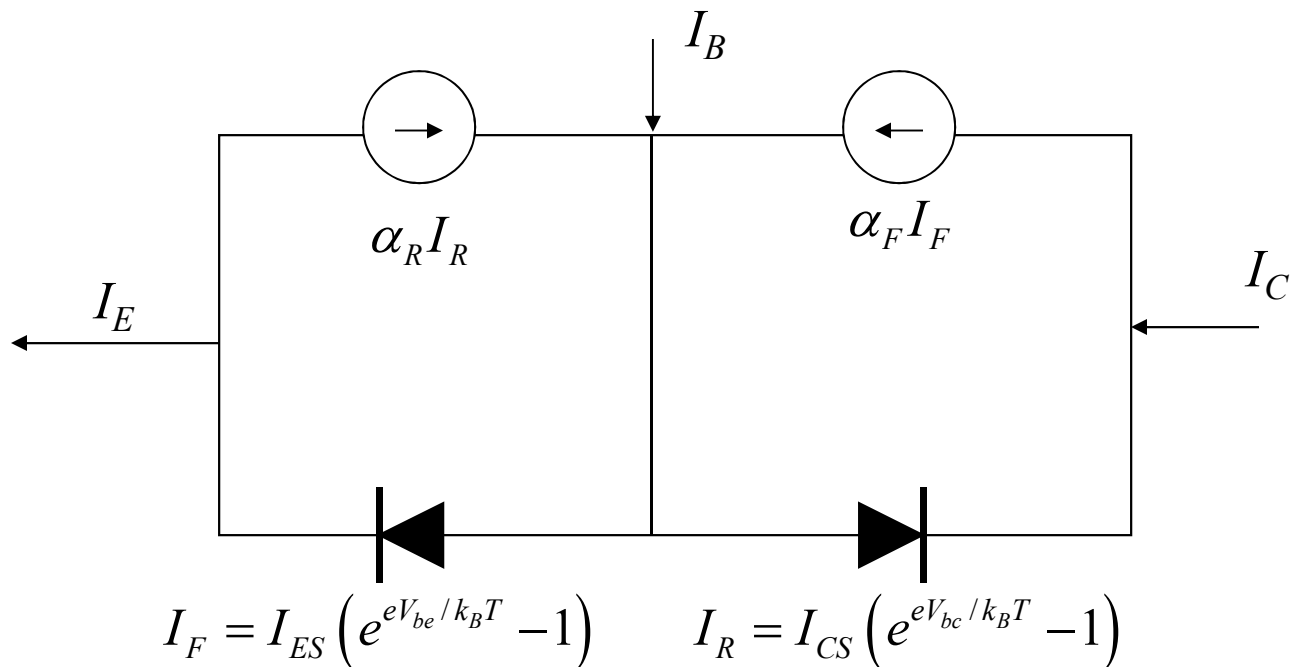


Ebers-Moll model

$$I_E = I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - \alpha_R I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right)$$

$$I_C = \alpha_F I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right)$$

$$I_B = I_E - I_C$$



Emitter efficiency

$$\gamma_e = \frac{I_{En}}{I_{En} + I_{Ep}} = \frac{1}{1 + I_{Ep} / I_{En}} \quad \leftarrow \text{for npn}$$

$$I_{Ep} = eA_{be}D_p \frac{p_{e0} \left(e^{eV_{be}/k_B T} - 1 \right)}{W_{eb} - x_e}$$

$$I_{En} = -eA_{be}D_n \frac{n_{b0} \left(e^{eV_{be}/k_B T} - e^{eV_{bc}/k_B T} \right)}{W_{bc} - W_{be}}$$

For $\gamma_e \sim 1$, $W_{bc} - W_{be} \ll L_b$, $W_{eb} - x_e$ and $n_{b0} \gg p_{e0}$

neutral base width

$$\frac{n_i^2}{N_{Ab}}$$

$$\frac{n_i^2}{N_{De}}$$

Small base width and heavy emitter doping

Base transport factor

$$B = \frac{I_c}{I_{En}}$$

ratio of the injected current to the collected current

recombination in the base would reduce the base transport factor

A thin base with low doping results in a base transport factor ~ 1

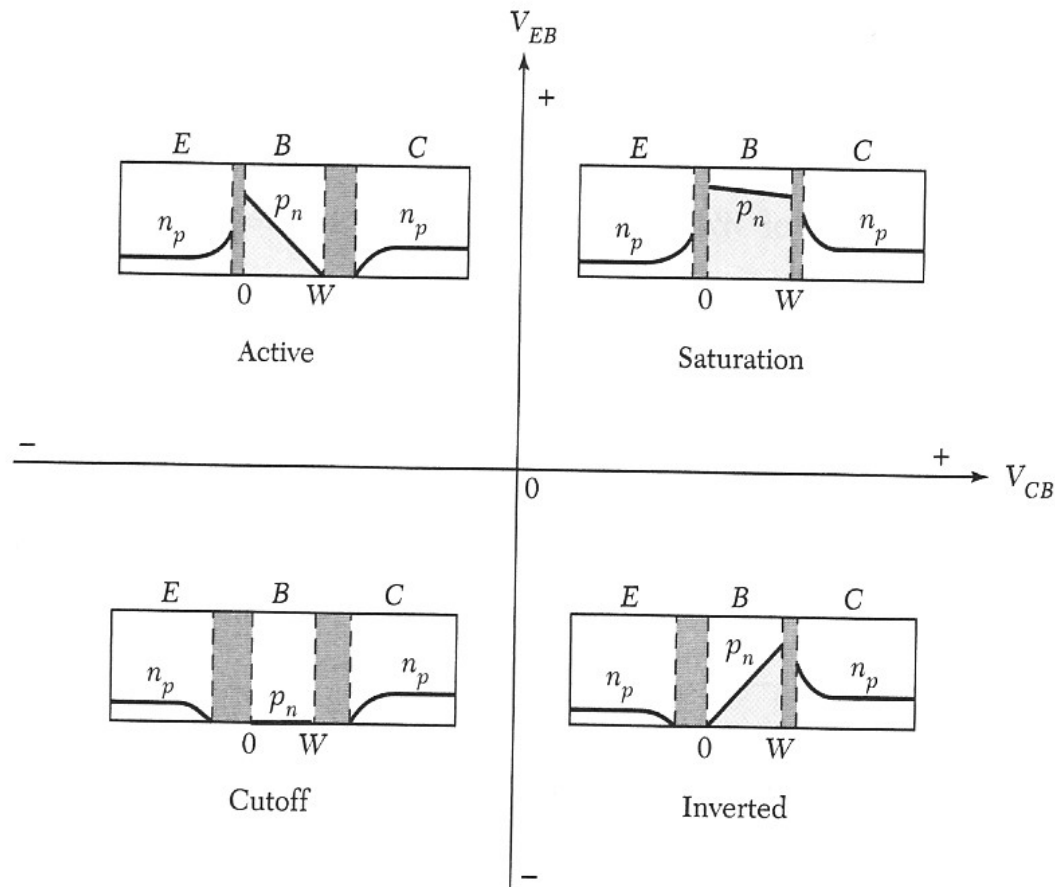
Current transfer ratio

$$\alpha = \frac{I_C}{I_E} = B\gamma_e$$

$\alpha \sim 1$ for a good BJT

Transistor modes

1. Forward active: emitter-base **forward**, base-collector **reverse**
2. Saturation: emitter-base **forward**, base-collector **forward**
3. Reverse active: emitter-base **reverse**, base-collector **forward**
4. Cut-off: emitter-base **reverse**, base-collector **reverse**

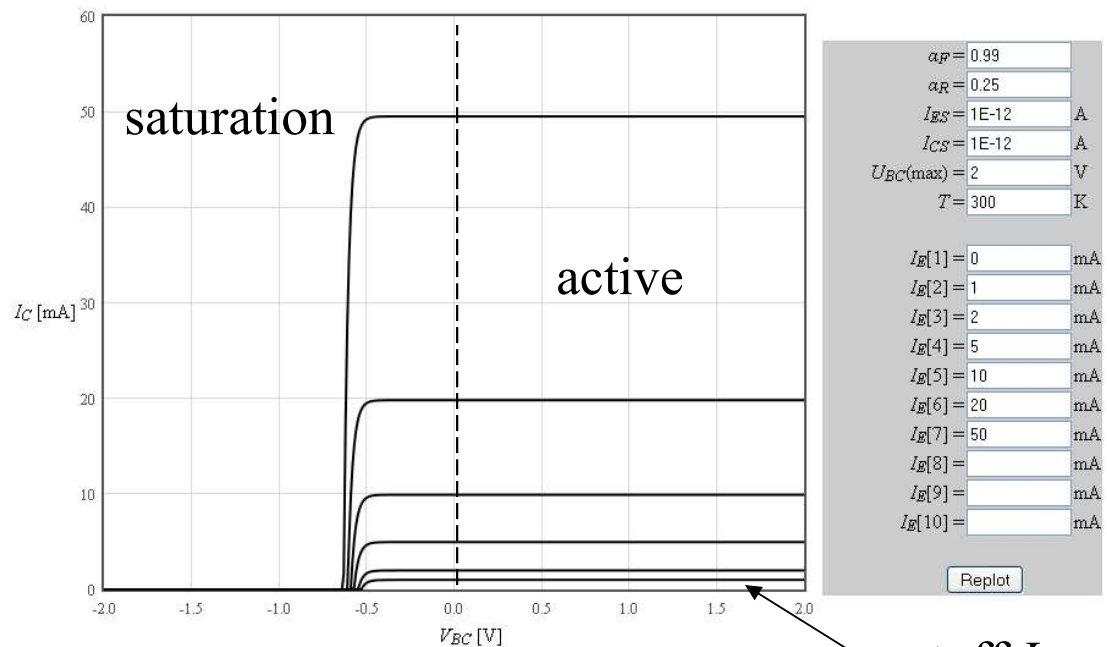
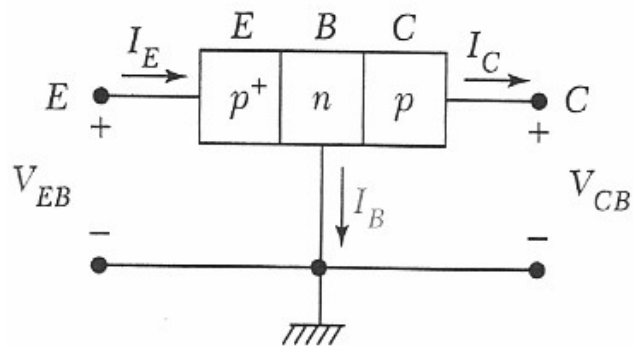


Common base configuration

$$I_E = I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - \alpha_R I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right)$$

solve for V_{be}

$$I_C = \alpha_F I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right)$$



cutoff $I_E < 0$

Ebers - Moll Model

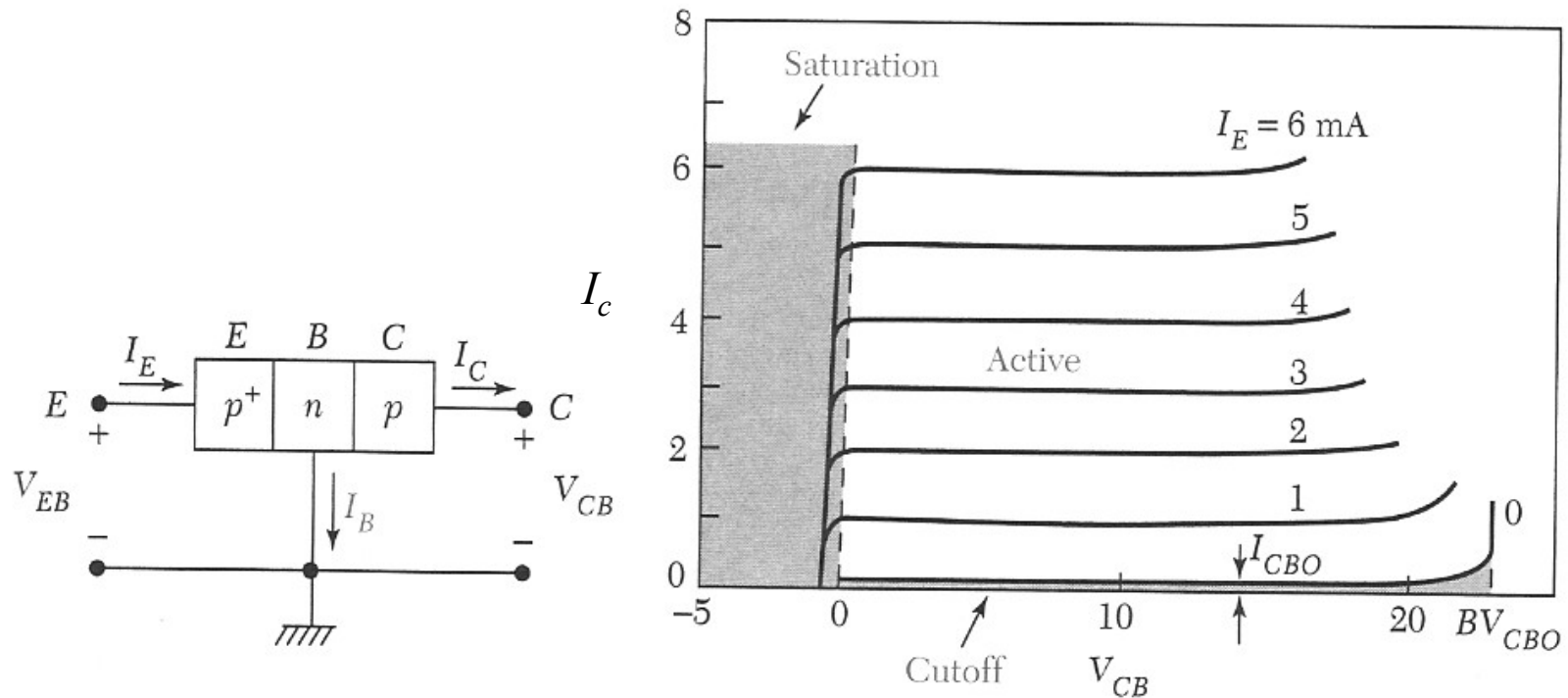
$$I_{ES} = \left[\frac{eA_{be}D_p p_{e0}}{W_{eb} - x_e} + \frac{eA_{be}D_n n_{b0}}{W_{bc} - W_{be}} \right]$$

$$\alpha_R I_{CS} = \frac{eA_{be}D_n n_{b0}}{W_{bc} - W_{be}}$$

$$\alpha_F I_{ES} = \frac{eA_{bc}D_n n_{b0}}{W_{bc} - W_{be}}$$

$$I_{CS} = \left[\frac{eA_{bc}D_p p_{c0}}{x_c - W_c} + \frac{eA_{bc}D_n n_{b0}}{W_{bc} - W_{be}} \right]$$

Common base configuration

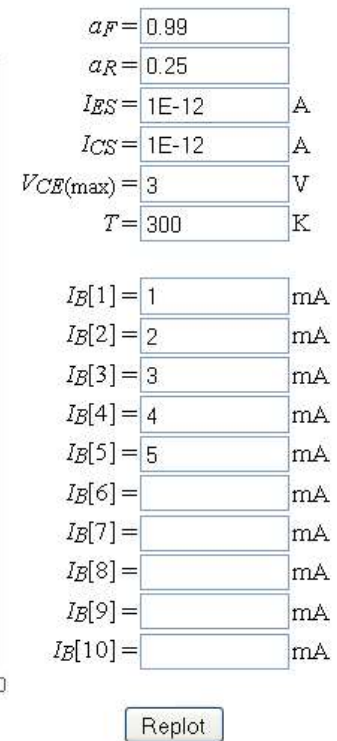
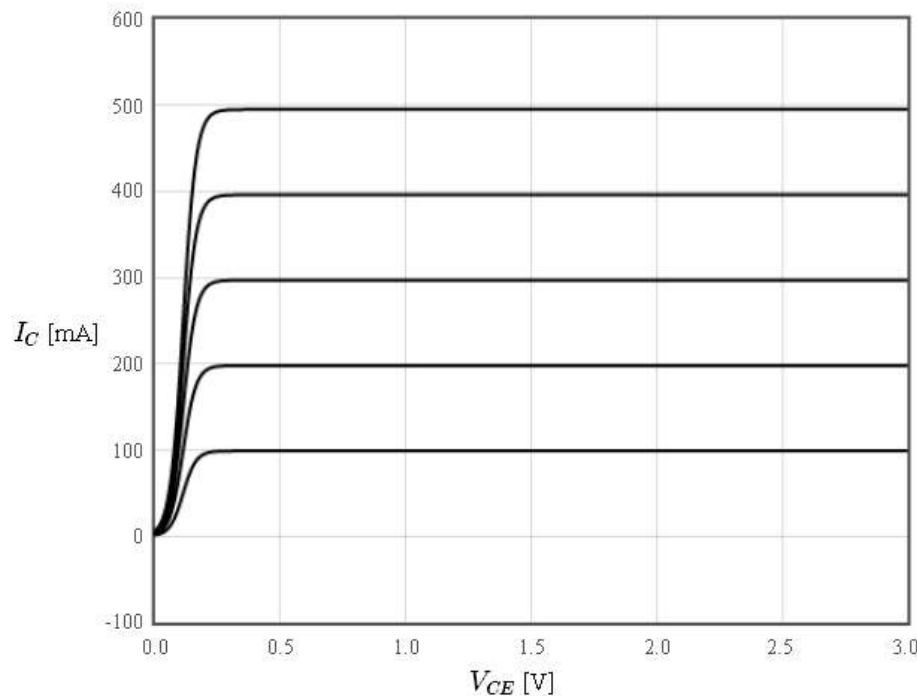
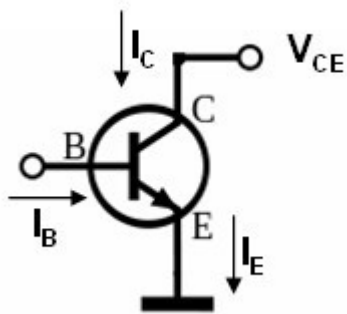


$I_C \sim I_E$ buffer circuit: the output current is constant over a wide range of output voltages

Common emitter configuration

$$I_E = I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - \alpha_R I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right) \quad I_B = I_E - I_C$$

$$I_C = \alpha_F I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right)$$



current amplification ~ 100

Current amplification factor

$$\beta = h_{fe} = \frac{I_C}{I_B}$$

$$I_B = I_E - I_C$$

$$I_C = \alpha I_E$$

$$I_B = \left(\frac{1}{\alpha} - 1 \right) I_C$$

$$\beta = \frac{I_C}{I_B} = \frac{\alpha}{1 - \alpha} = \frac{B\gamma_e}{1 - B\gamma_e}$$

$$\beta \sim 50 - 500$$

Transconductance

$$g_m = \frac{\partial I_C}{\partial V_{be}}$$

$$I_c = \alpha_F I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right)$$

At a typical operating point, the first term usually dominates

$$I_c \approx \alpha_F I_{ES} e^{eV_{be}/k_B T}$$

$$g_m = \frac{e \alpha_F I_{ES}}{k_B T} e^{eV_{be}/k_B T} \approx \frac{e I_C}{k_B T} = \frac{e \beta I_B}{k_B T}$$

The transconductance can be very high.

Early effect

Ebers - Moll:

$$I_E = I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - \alpha_R I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right)$$

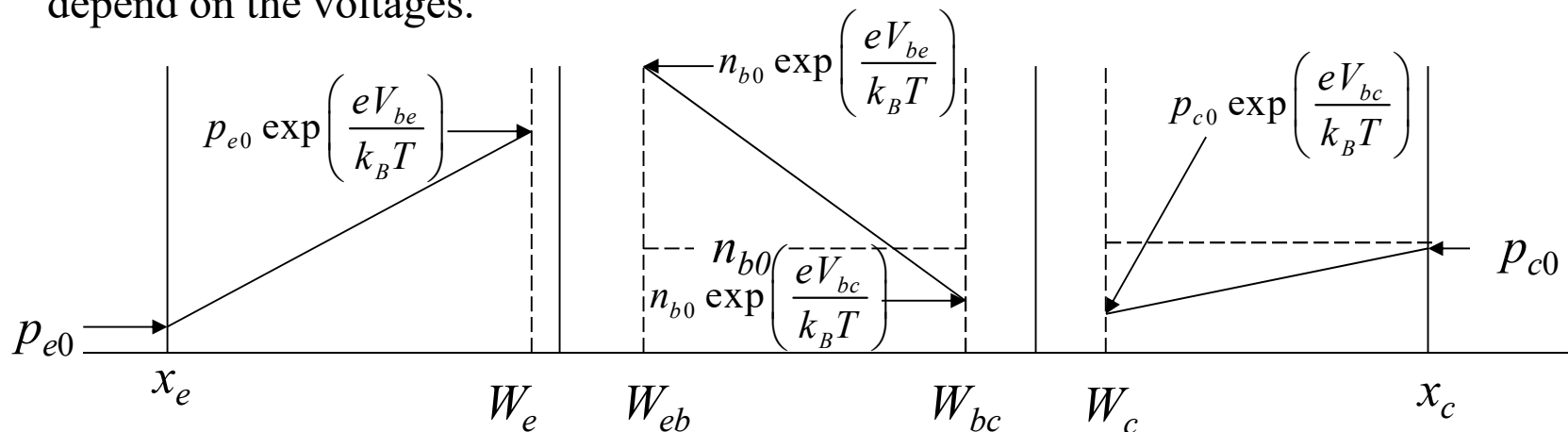
$$I_C = \alpha_F I_{ES} \left(e^{eV_{be}/k_B T} - 1 \right) - I_{CS} \left(e^{eV_{bc}/k_B T} - 1 \right)$$

$$I_B = I_E - I_C$$

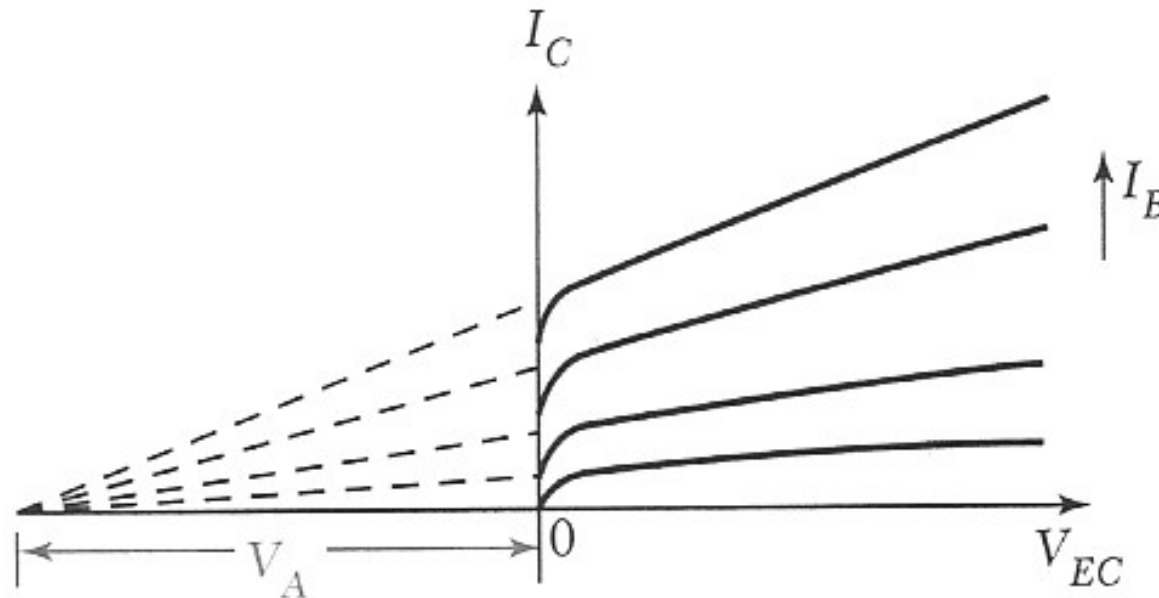
$$I_{ES} = \left[\frac{eA_{be}D_p p_{e0}}{W_{eb} - x_e} + \frac{eA_{be}D_n n_{b0}}{W_{bc} - W_{be}} \right]$$

$$I_{CS} = \left[\frac{eA_{bc}D_p p_{c0}}{x_c - W_c} + \frac{eA_{bc}D_n n_{b0}}{W_{bc} - W_{be}} \right]$$

I_{ES} and I_{CS} are treated as constants but the depletion widths W_{bc} , W_{be} , W_c , and W_e depend on the voltages.



Early effect



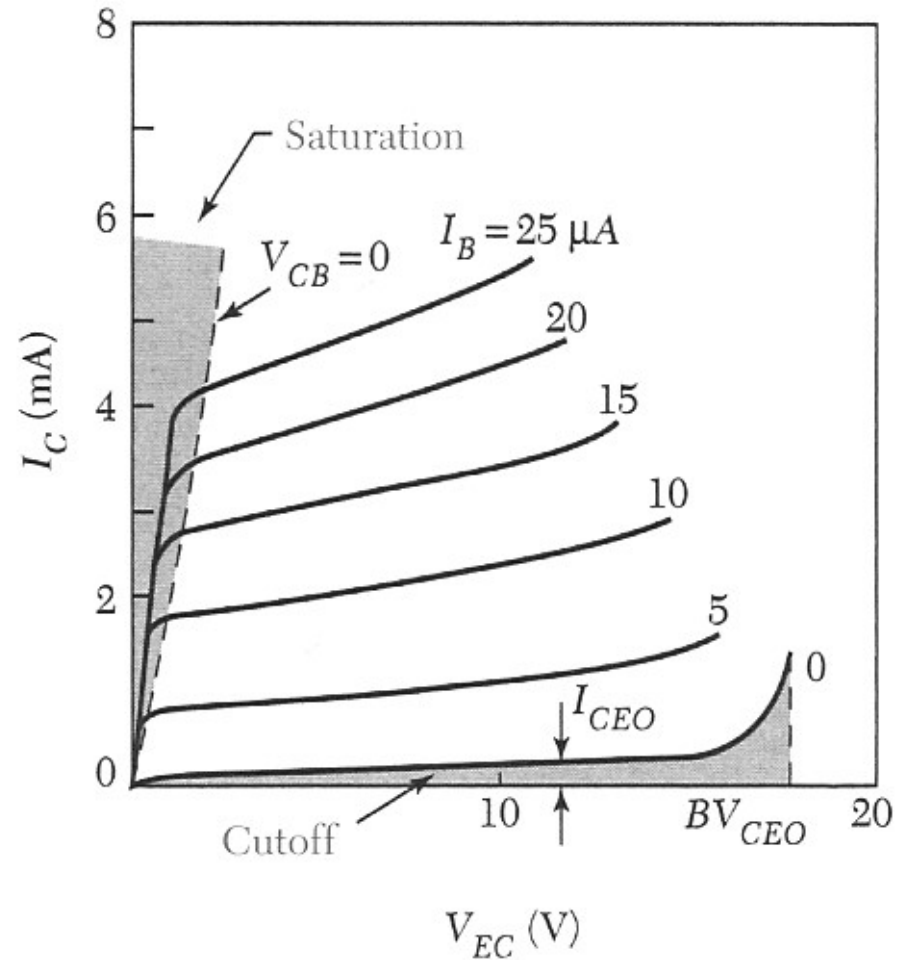
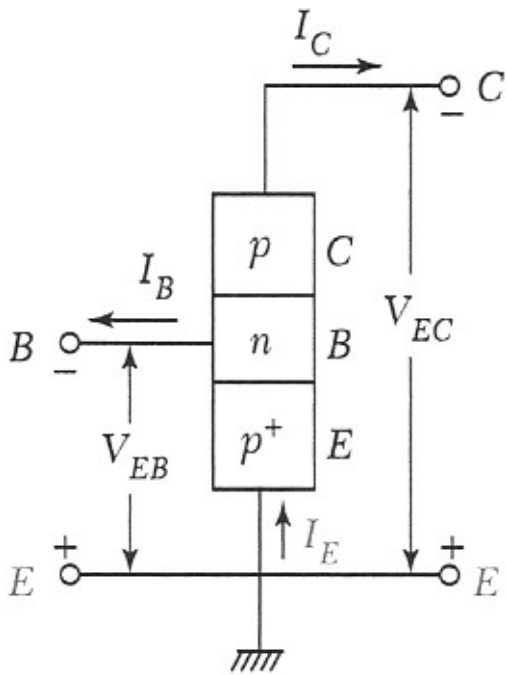
Common emitter configuration

Base width modulation: smaller width increases the diffusion current and increases the gain.

Punchthrough: The neutral base width goes to zero and all gain is lost.

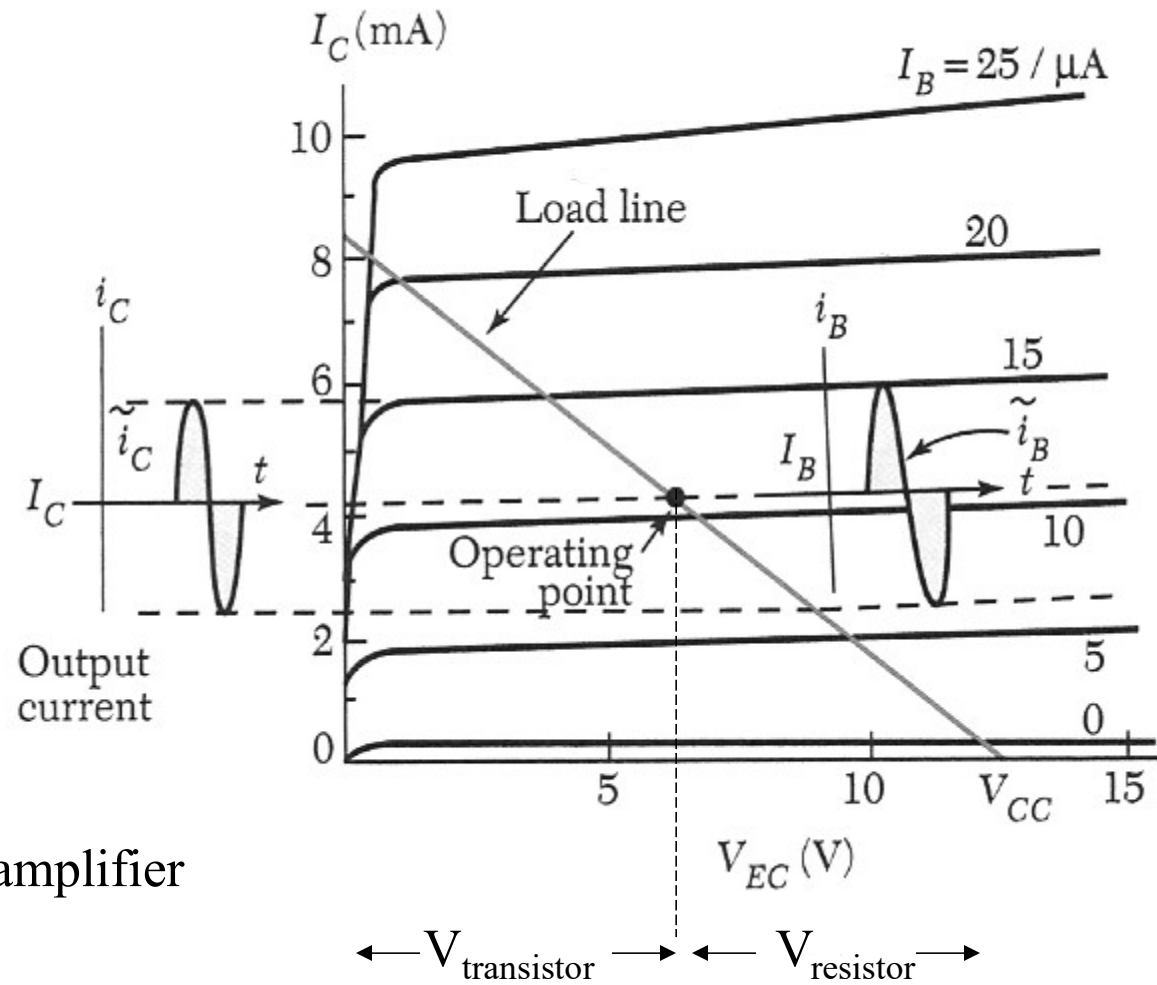
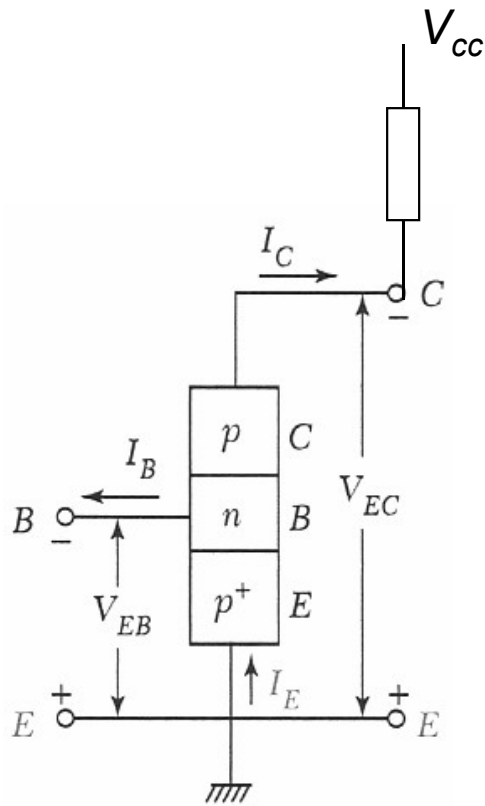
Lightly dope the collector -> voltage drops in collector. Makes circuit slower.

Common emitter configuration

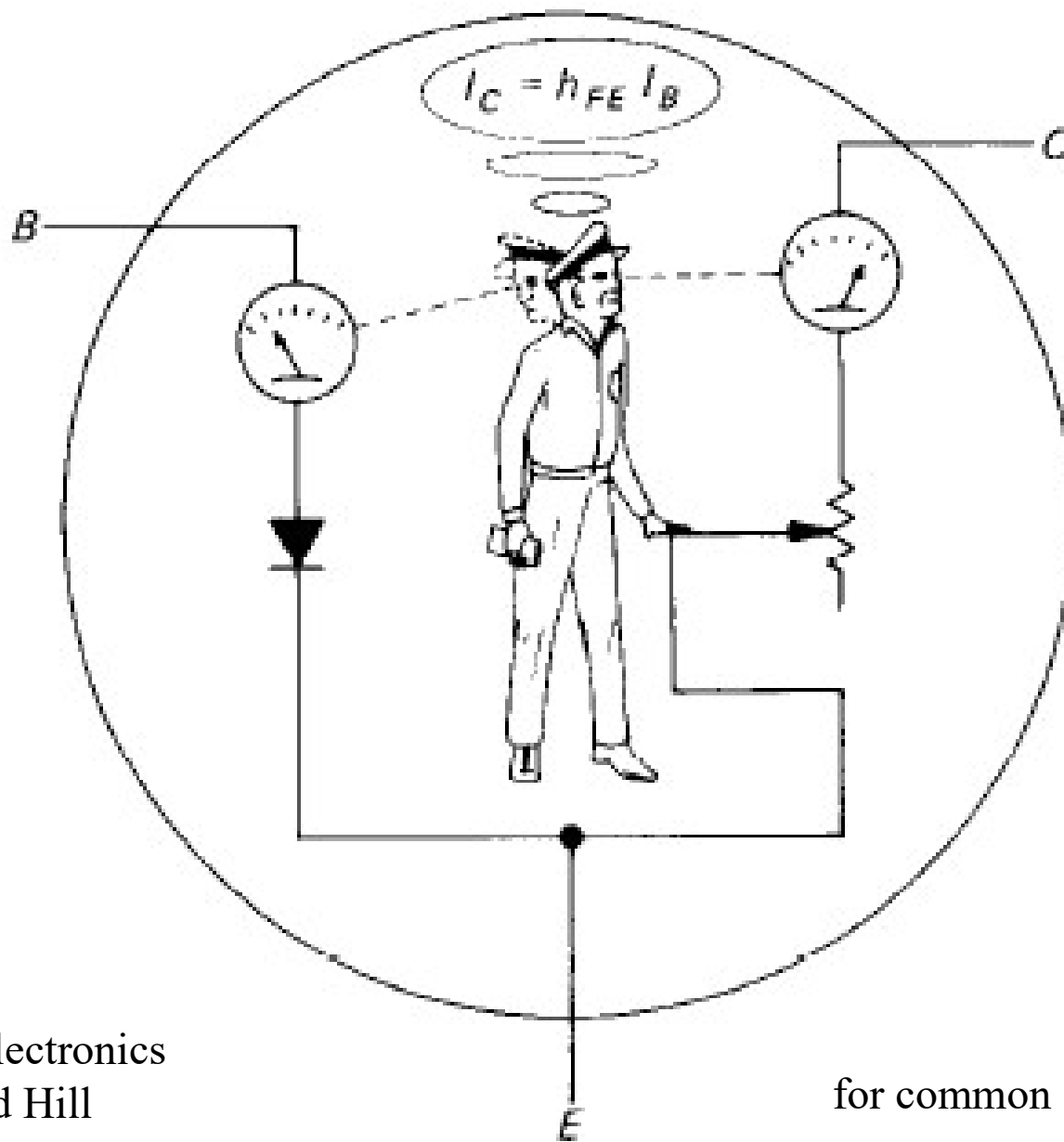


$$I_C \sim \beta I_B \text{ amplifier}$$

Small signal response



Low input impedance amplifier



The Art of Electronics
Horowitz and Hill

for common emitter configuration

“Transistor man”

Small signal response

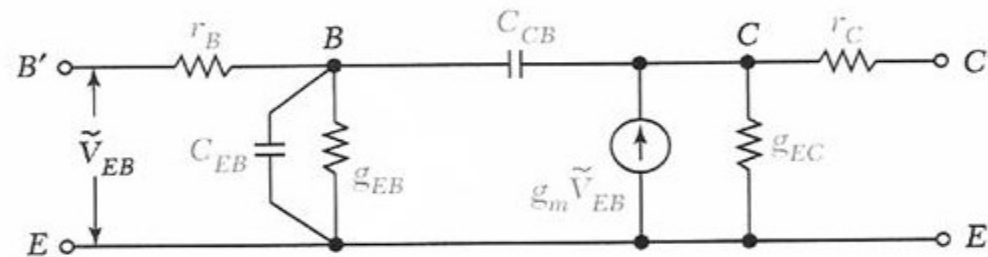
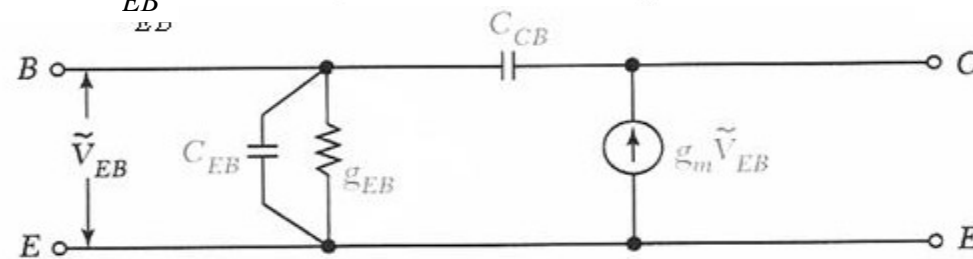
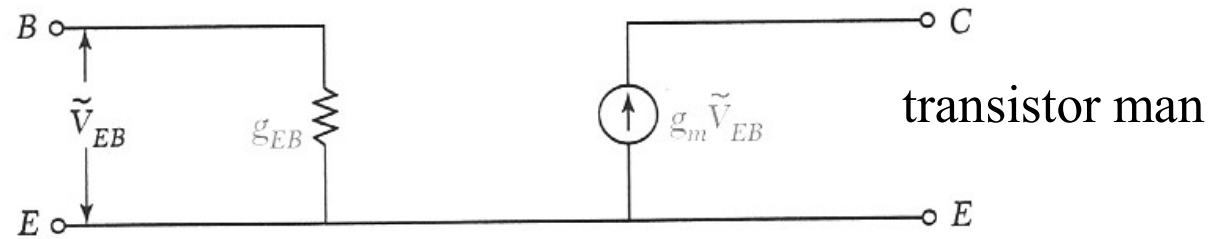
$$\tilde{i}_c = \beta \tilde{i}_B = \beta g_{EB} \tilde{v}_{EB}$$

input conductance:

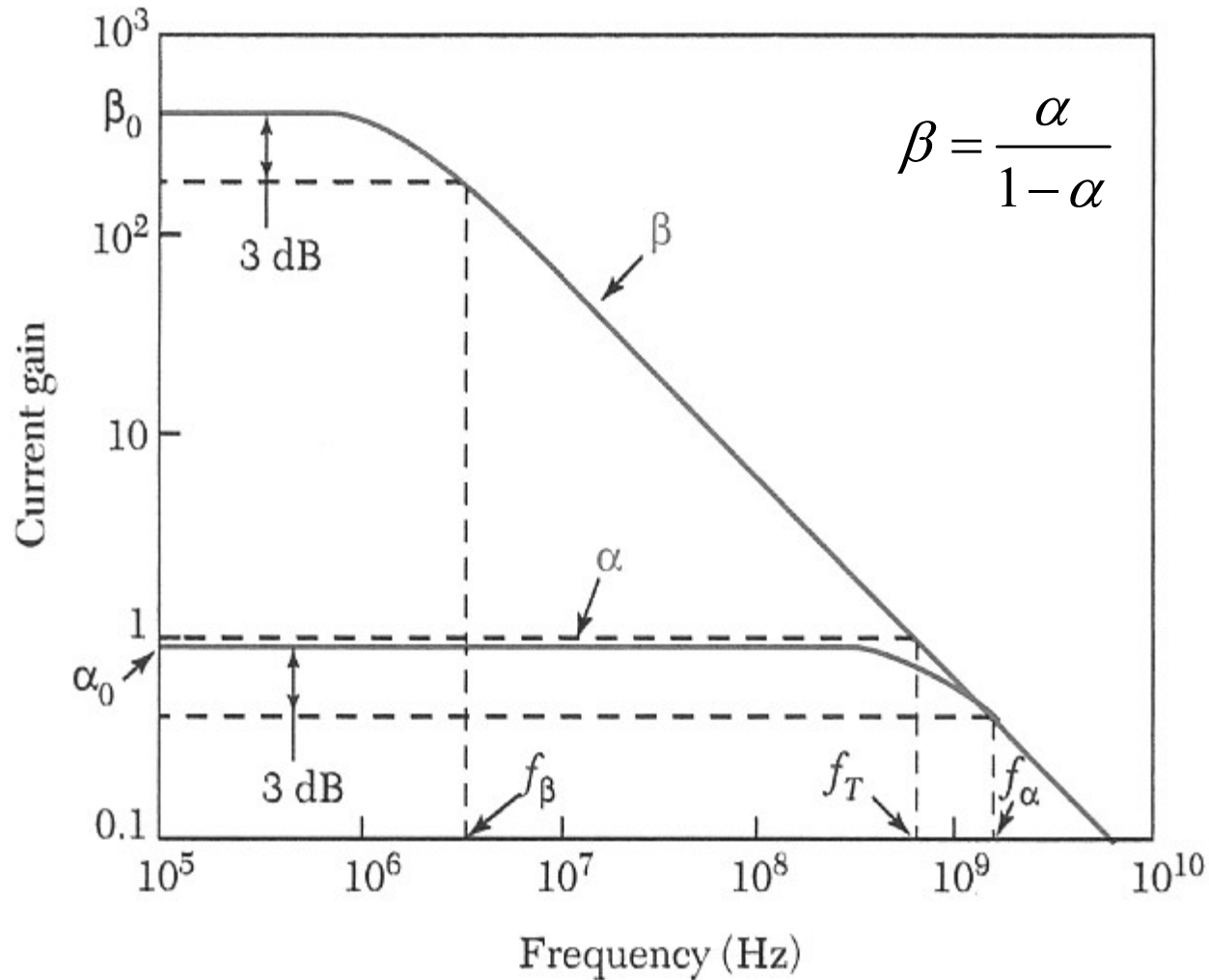
$$g_{EB} = \frac{\tilde{i}_B}{\tilde{v}_{EB}}$$

transconductance:

$$g_m = \frac{\tilde{i}_c}{\tilde{v}_{EB}}$$



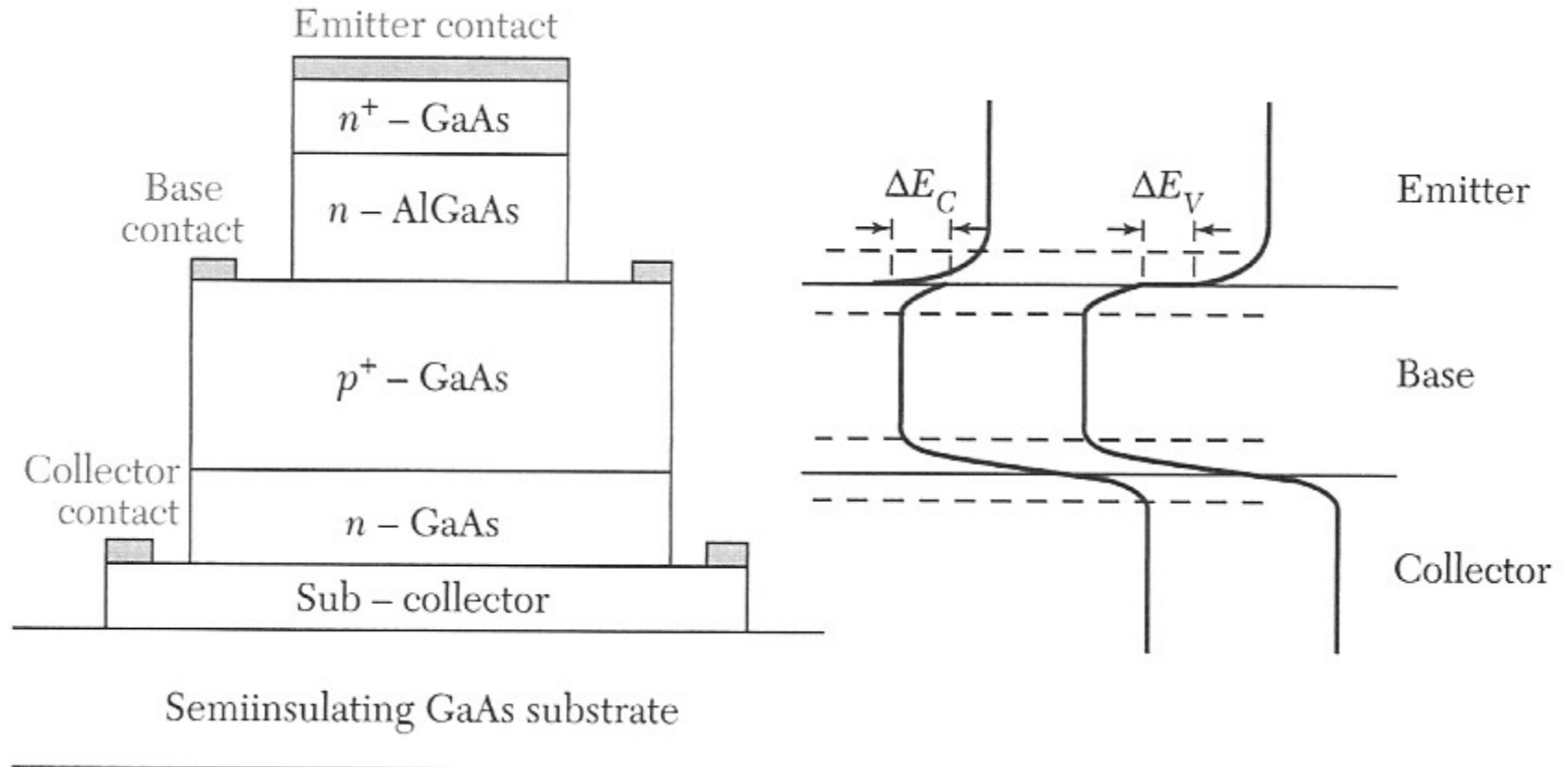
Small signal response



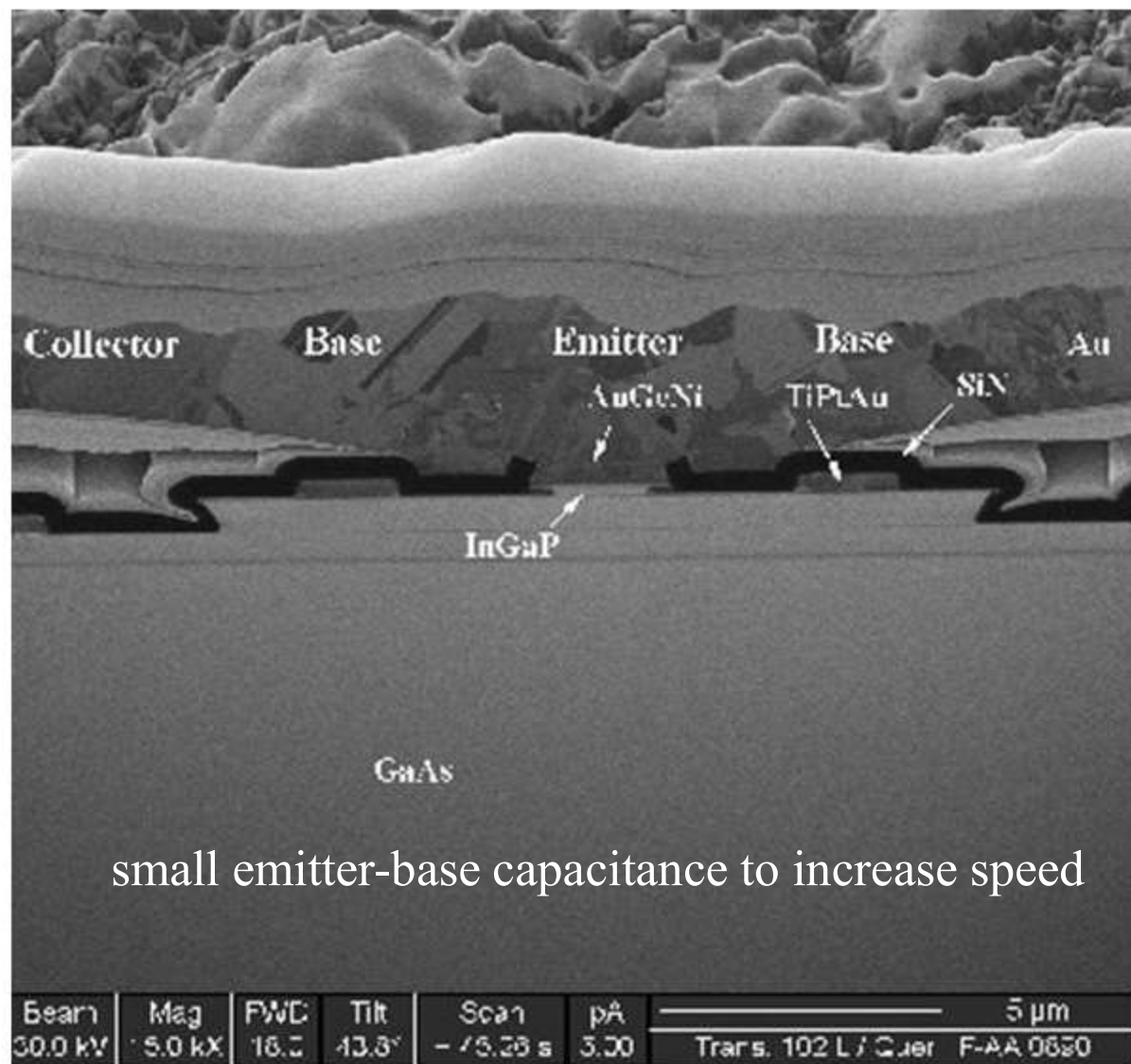
$$f_\beta = (1 - \alpha_0) f_\alpha$$

$$f_T = \alpha_0 f_\alpha$$

Heterojunction bipolar transistors



Heterojunction bipolar transistor



HBT current gain

$$I_C = \beta I_B$$

$$\beta = \frac{\alpha}{1-\alpha} \approx \frac{n_{B0}}{p_{E0}} \quad (\text{npn})$$

Higher doping in the emitter makes the minority carrier concentration lower in the emitter.

$$n_{B0} = \frac{n_i^2}{N_A} = \frac{N_C N_V \exp(-E_{gB} / k_B T)}{N_A}$$
$$p_{E0} = \frac{n_i^2}{N_D} = \frac{N'_C N'_V \exp(-E_{gE} / k_B T)}{N_D}$$

If the emitter and the base have different band gaps

$$\beta = \frac{N_E}{N_B} \frac{N_c N_v}{N'_c N'_v} \exp\left(\frac{\Delta E_g}{k_B T}\right) \sim 100000$$